Joint ICTP-IAEA School on Novel Experimental Methodologies for Synchrotron Radiation Applications in Nano-science and Environmental Monitoring | (smr 2611)

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Quantitative XRF analysis: algorithms and their practical use

Thursday, 20 November 2014 16:00 (1:00)

Content

Summary

Presenter(s): P. VAN ESPEN (University of Antwerpen - Belgium)

Session Classification: not yet classified